

**Search Notes**

Application/Control No.

10/511,365

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under  
Reexamination

TEN DOLLE ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	252	1/4/2006	HN
330	301	1/8/2006	HN
330	311	1/8/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	1/4/2006	HN